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PATENT

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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Allan Rosencwaig et al.

Application No.: 09/629,407

Filed: August 1, 2000

For: MEASUREMENT OF THIN FILMS  
AND BARRIER LAYERS ON  
PATTERNED WAFERS WITH  
X-RAY REFLECTOMETRY

Group No.: 2876

Examiner: H.K. Song

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